

Silicon Carbide JFETs enable  
breakthroughs of high-voltage solid state  
power distribution

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**Bodo's  
Wide Bandgap  
Event 2025**

*Making WBG Designs Happen*

***sic***

# Solid State Power Distribution

*Why to change a 100-year old, proven electro-mechanical concept*



- **Reduction of Fault isolation delay from  $>10$  ms to  $<5$   $\mu$ s**
  - Minimal current overshoot
  - Reduced Distortion in the distribution grid
  - Selectivity vs. Electronic Sources
- **Smart Protection Mechanisms**
  - Auto-Retry / Failure Recovery
  - Smart Inrush Handling
  - Self Diagnostic
- **Arc-Free, Wear-free Actuation and Protection**
  - Reduced Maintenance
  - Installation Space (IT environment)
  - Smart Load Control
- **AC and DC compatible**

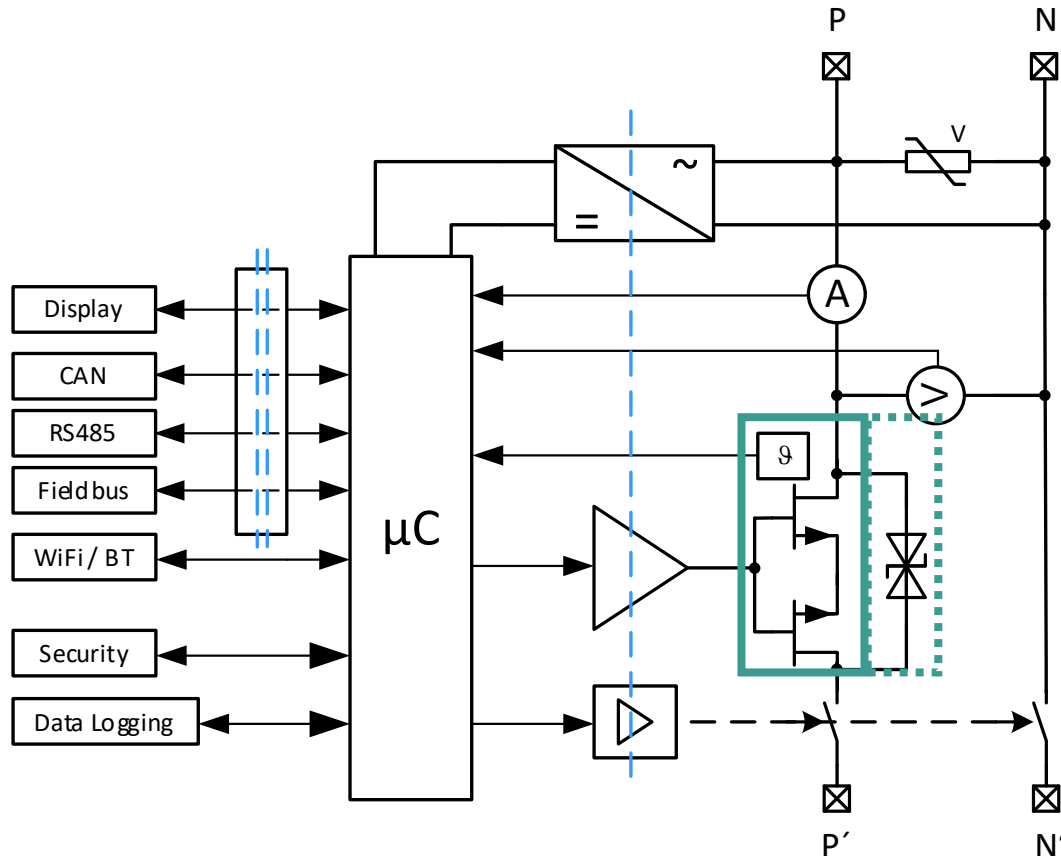
- **Size / Ampacity**
- **Power Dissipation**
- **Cost (CAPEX)**



**Enabled by  
Power Semiconductor  
Solutions**

# Solid State Circuit Breakers from a System Perspective

*Power Stage as critical building block*



## SSCB Requirement

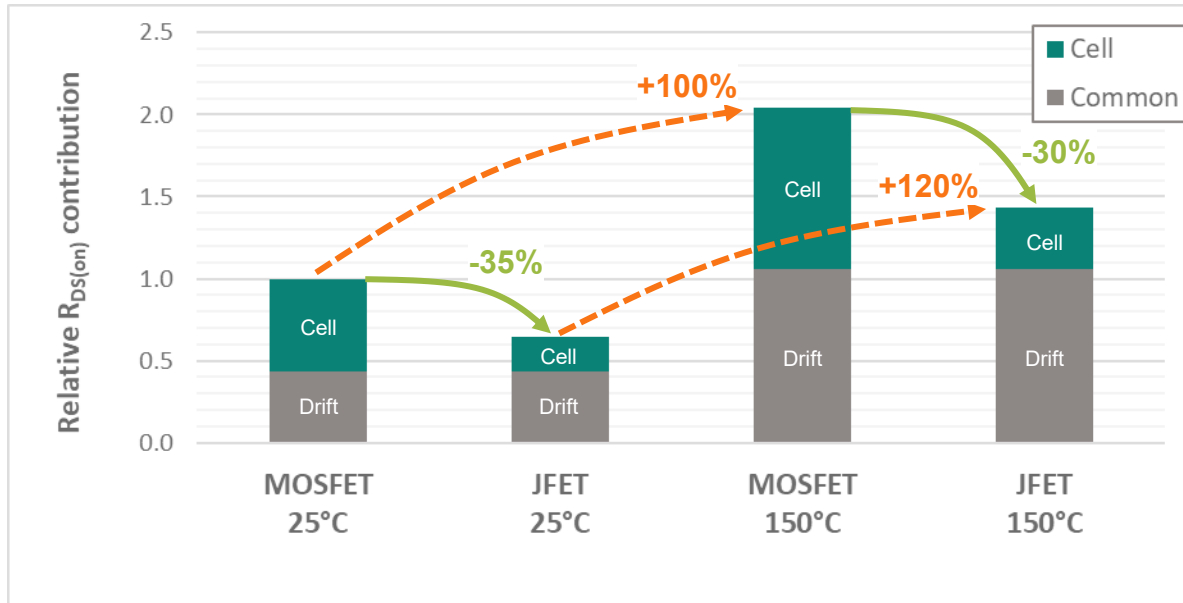
- Very low Voltage drop @ rated current
- Overload Capability
- High Current Switching Capability
- Interplay with Clamping Device
- Overvoltage / Overcurrent Robustness
- Power Temperature Cycle Robustness
- Miniature Solution Size
- Lifetime equivalent to EM solution

## Example: 63A/800 Vdc

- 150 mV/Pole
- 2.3 mΩ total
- $3 \times I_{nom} \cdot 2s$
- $I_{SD} = 1 \text{ kA}$
- TVS
- OVC III
- 500kc @ 125 °C
- Equivalent to 63A MCB
- >20 years \* 24/7

# JFET: Advancements in $R_{on} \cdot A$ and FBSOA

## $R_{DS(on)}$ Contribution: 1.2kV CoolSiC™ MOSFET vs. JFET

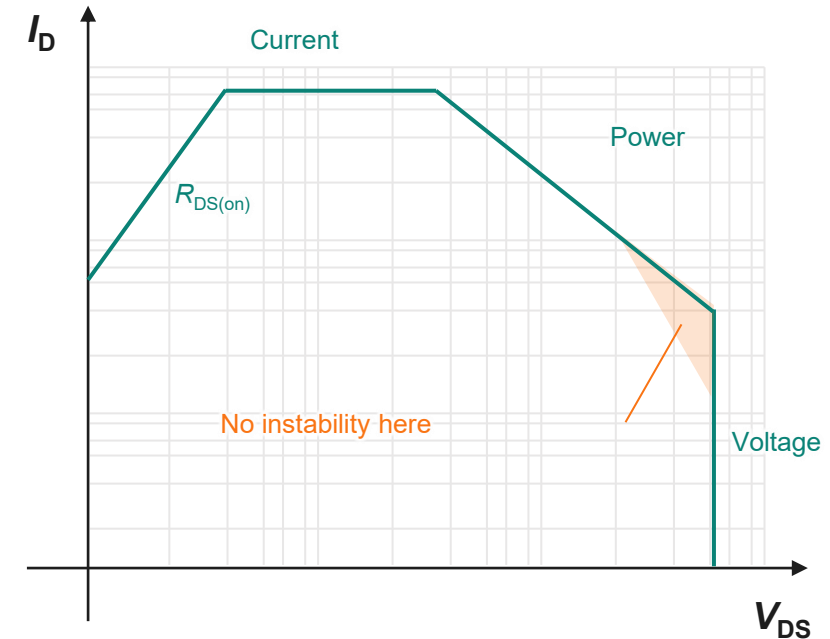


Best-in-Class  $R_{DS(on)}$  Ratings:

2.3mΩ @ 1200V  $V_{BDSS}$

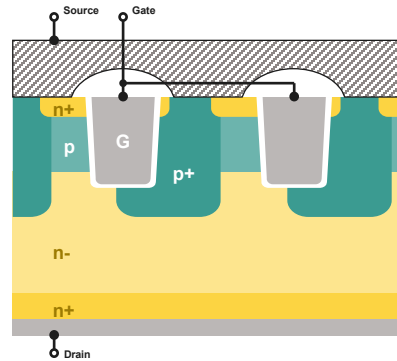
1.5mΩ @ 750V  $V_{BDSS}$

## JFET FBSOA: $I_D$ vs. $V_{DS}$

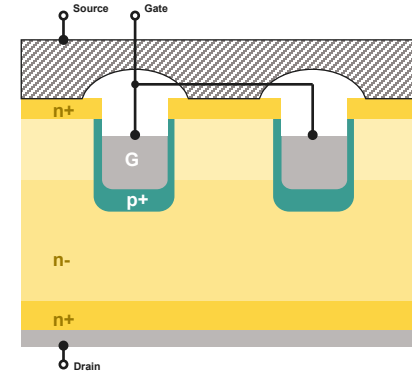


- Thermal Stability under all operating conditions
  - No hot-spotting during overload pulses
  - Linear mode capable
  - Stable operation in “avalanche”




# Technology differentiation – CoolSiC™ JFET vs. MOSFETs



SiC MOSFETs

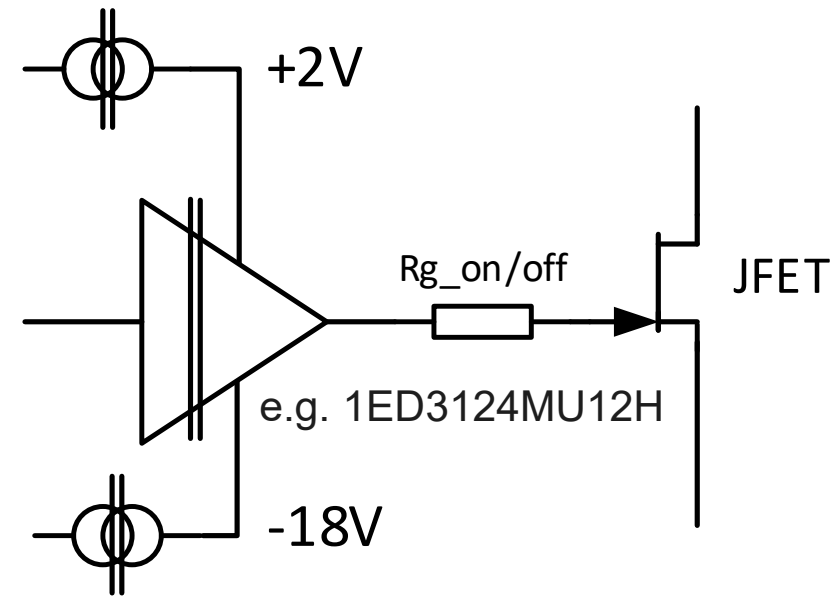
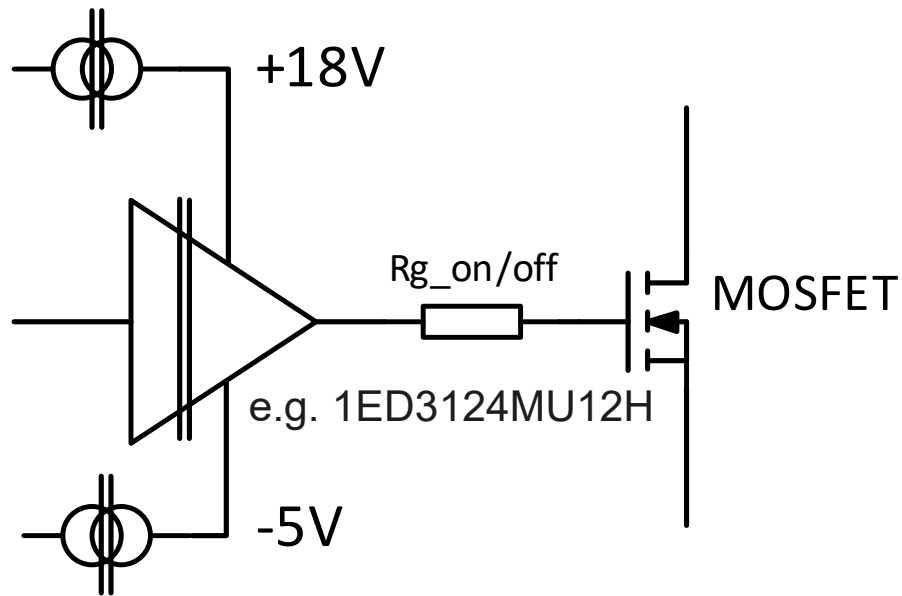


SiC JFETs

<b>Construction</b>	<p>Channel conduction, normally off</p> <p>Fully isolated gate</p> <p>Optimized for minimum gate feedback</p>	<p>Bulk conduction, normally on</p> <p>Non isolated gate</p> <p>Optimized for <math>R_{DS(on)}</math> and robustness</p>
<b>FOMs</b>	<p>Relatively high(er) <math>R_{DS(on)}</math></p> <p>Lower temperature coefficient</p>	<p>Lowest possible <math>R_{DS(on)}</math> per device</p> <p>Higher temperature coefficient</p>
<b>Benefits</b>	<p>Simplified control, high switching speed</p> <p>Compatibility to legacy circuits</p>	<p>Maximum power density </p> <p>Active clamping </p> <p>Linear mode operation </p>

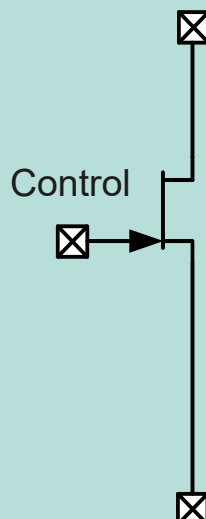
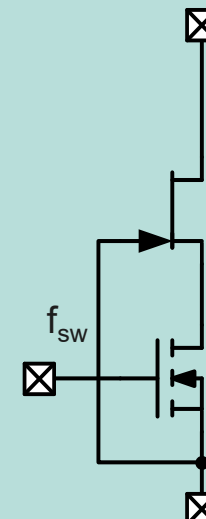
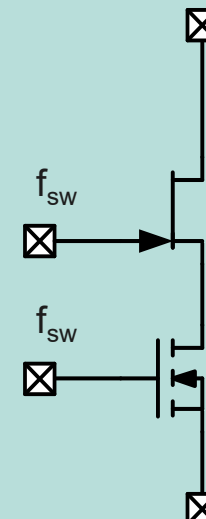
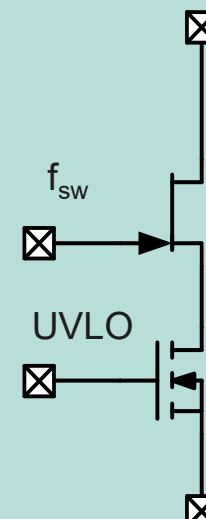
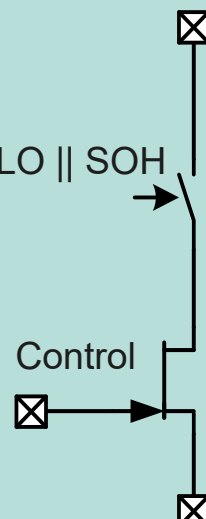
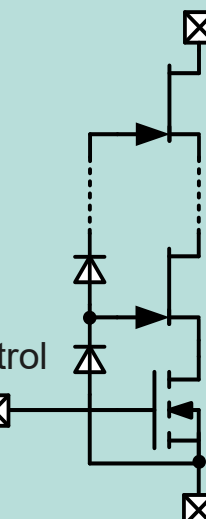
# Driving a CoolSiC™ JFET is easy...

*Example: Isolated Gate Drive Scheme*



- Exchange Polarity of Supply voltages: +18V → -18V; -5V → +2V
- Adoption of Rg\_on and Rg\_off values
- Use of same (basic) Gate Driver

# Drive modes and application mapping for JFET/JFET Cascodes

Topology	 <p>Bare Bone</p>	 <p>Cascode</p>	 <p>Direct Drive</p>	 <p>Safety Cascode</p>	 <p>SSCB w/ airgap and safety disconnect</p>	 <p>Super Cascode</p>
Application	<ul style="list-style-type: none"> <li>› Motor starters</li> <li>› Drives</li> </ul>	<ul style="list-style-type: none"> <li>› SMPS</li> </ul>	<ul style="list-style-type: none"> <li>› SMPS</li> <li>› Drives</li> </ul>	<ul style="list-style-type: none"> <li>› eFuse</li> <li>› SSCBs</li> <li>› Drives</li> </ul>	<ul style="list-style-type: none"> <li>› SSCBs</li> </ul>	<ul style="list-style-type: none"> <li>› HV-SSCBs</li> </ul>



# Package Optimization for full application performance

*Q-DPAK enables efficient system integration into SSCB assemblies*



## Large Drain and Source interface area

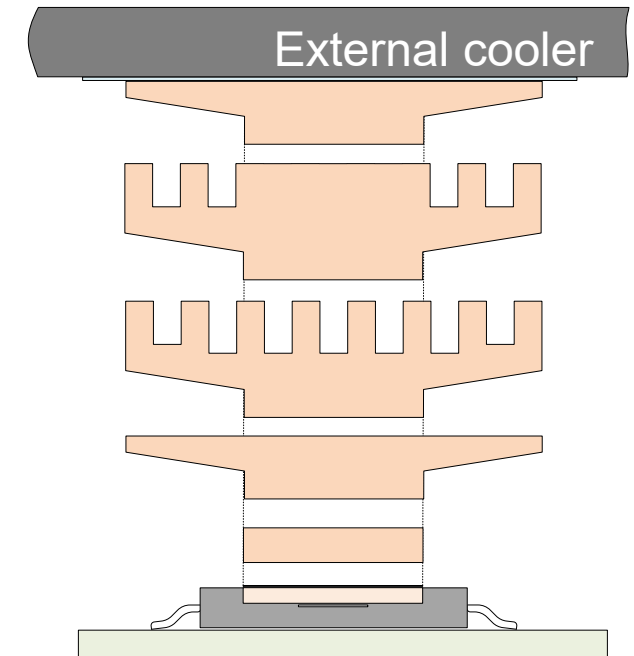
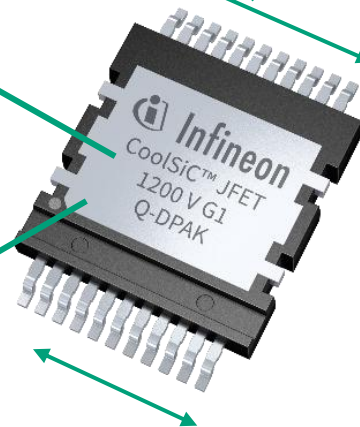
- Minimize Losses
- Reduced current density at the interface

## Optimized internal construction

- High current interfaces
- Diffusion soldering
- Large die area & internal paralleling

## Top-Side Cooling & large heatslug

- Lowest possible  $R_{th}$
- Directly connected, local  $C_{th}$
- Application-adjustable  $C_{th}$



- Directly attached TSC cooler enables flexibility
  - Adjust  $i^2t$  capability via  $C_{th}$  extension
  - Optimize  $R_{th}$
  - Reduce Thermal cycling stress



# Summary

- Solid-State Power Distribution is a new emerging application field with special requirements to the applied semiconductors
  - Ultra-Low  $R_{DSon}$  of HV Power Transistors
  - Robustness and Reliability under heavily exposed conditions
- The CoolSiC™ JFET enables high performance SSCB designs by
  - Groundbreaking low  $R_{DSon}$  values
  - Simplified device paralleling
  - High Current Avalanche Ratings to minimize the effort in clamping solutions
- The Q-DPAK Package is optimally suited for the implementation of high current SSCBs
  - Large routing interface area on both, Drain and Source contacts
  - Large thermal interface area
  - User-extendable thermal capacitance for overload capability.

